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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants : Banqiu Wu et al.
Serial No. : 10/644,358
Filing Date : August 20, 2003
Title : ENDPOINT DETECTION OF PLASMA-ASSISTED
ETCH PROCESS
Examiner : Stephen D. Rosasco
Group Art Unit : 1756

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Date of Deposit:	August 13, 2004
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Name:	Gerri Renna
Signature:	

STATUS INQUIRY

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Applicant respectfully inquires as to the status of the above-identified application.
The Filing Receipt was mailed on September 16, 2003. Applicant's attorney has not received an Examiner's communication from the Patent Office since that date.

Respectfully submitted,

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August 13, 2004

By

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